

In the Specification:

Please insert before the first paragraph of the application:

This application is the national stage application of international application number PCT/DE2003/002112, filed on June 25, 2003, which claims the benefit of priority to German Patent Application DE 102 28 284.6, filed on June 25, 2002, both of which are incorporated herein by reference.

Please amend paragraph on page 4 line 37 and page 5 line 6.

However, these self-heating test structures have the disadvantage that ~~in them~~ two of the quantities which influence electromigration are coupled to one another. It is not possible to increase the electrical current density in the conductive structure independently of the temperature. Every increase in the electrical current density also leads to an increase in the temperature of the conductive test structure. This leads to a restriction of the parameter space of the quantities to be investigated, which ~~restriction~~ is unacceptable.

Please delete the paragraph on page 5, lines 31-35.

~~The problem is solved by means of an electromigration test apparatus and an electromigration test method having the features in accordance with the independent patent claims.~~

Please amend the paragraph on page 5, line 7.

An electromigration test apparatus according to the invention has a direct-current source and an alternating-current source. Furthermore, the test apparatus has a circuit. The latter has at least one conductive structure to be tested, which is electrically conductively connected to the direct-current source and the alternating-current source. Furthermore, the test apparatus has a measuring device, which is set up in such a way that it detects an electrical parameter, which. The parameter is indicative of electromigration in the test structure. In the electromigration test arrangement, the AC voltage source is set up in such a way that it exposes the conductive structure to be

tested to an alternating current, independently of a direct current of the direct-current source. By means of the alternating current generated by the AC voltage source, the conductive structure to be tested is heated to a predetermined, preferably settable, temperature.

Please amend paragraph on page 6, lines 22, 26 and 25.

A method according to the invention for testing a conductive structure for electromigration has the following steps. A conductive structure to be tested is electrically coupled to an electrical circuit, which ~~electrical circuit~~ is electrically coupled to a direct-current source and an alternating-current source. In an additional step, the conductive structure to be tested is exposed to an electrical direct current, which ~~direct current~~ brings about the electromigration within the conductive structure to be tested. Furthermore, the method according to the invention exhibits heating of the conductive structure to be tested by means of an alternating current generated by the AC voltage source, the alternating current being independent of the direct current which causes the electromigration within the conductive structure to be tested. Furthermore, the method according to the invention has the step of detection of an electrical parameter, which ~~parameter~~ is indicative of the electromigration within the conductive structure to be tested.

Please delete paragraph on page 8, line 1-2.

~~Preferred developments of the invention emerge from the dependent claims.~~

Please amend the paragraph on page 13, line 1.

The following documents ~~is-are~~ cited in this document: